

Supplementary Material for the paper:

**Correction method for the self-absorption effects in
fluorescence extended X-ray absorption fine structure on
multilayer samples**

Figure S1 shows the correction factors $\alpha(k)$ for the EXAFS spectra of Cr/C multilayer measured at $\theta=3.0^\circ$, 5.0° , 10.0° . The structures of the correction factors are closely related with the EXAFS oscillation structures. However, some spikes can be found in the correction factor curves, which are just at the positions where χ_{expt} are very close to zero. In this correction method, the ratio of $(\chi_{\text{cal}} - \chi_{\text{expt}})/\chi_{\text{expt}}$ was used to judge the convergence, which resulted in these spikes. Even though some spikes exist in the correction factor curves, they have negligible effects on the corrected EXAFS spectra.

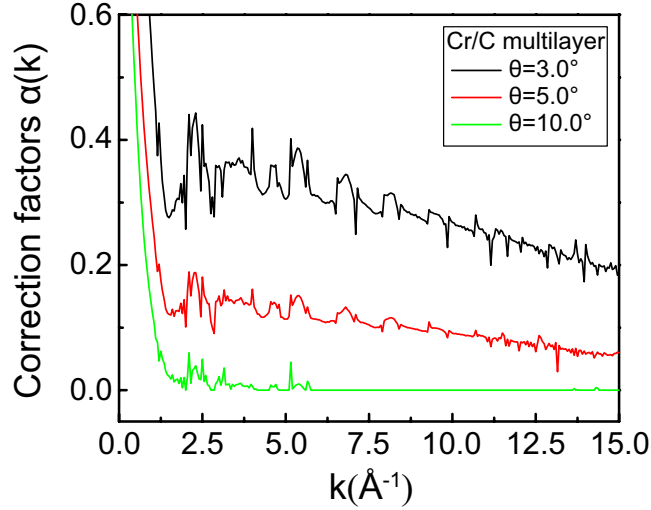


Figure S1: The correction factors for the EXAFS spectra of Cr/C multilayer measured at $\theta=3.0^\circ$, 5.0° , 10.0° .